Search Notes

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/768,626	PARK, CHANG-SIN	
Examiner	Art Unit	
Tuyet Vo	2821	

	SEAR	CHED	
Class	Subclass	Date	Examiner
315	248	5/30/2005	T> _
	267,246		
V	344		
219	660		
	661,663		
	702,707		
1	715,716		
V	760,761		V

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
magnetron/filament, electrodeless,microwave, AC/DC	5/30/2005	TV ·		